1	(New) The tip as recited in claim 11, wherein said tip includes a
2	dielectric band.
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1	(New) A thermokeratoplastic probe that can be used to denature a
2	cornea, comprising:
3	a handle;
4	a first connector attached to said handle;
5	a second connector that mates with said first connector; and,
6	a tip that is coupled to said second connector, said tip having a length
7	between 300 and 600 microns.
1	3 thermokeratorlasty 2
1	14. (New) The thermokeratoplastic probe as recited in claim 18, further
2	comprising a stop that limits an insertion depth of said tip into the cornea.
1	(New) The thermokeratoplastic probe as recited in claim 13,
2	wherein said tip is located at a distal end of a spring beam.
1	6. (New) A thermokeratoplastic system for denaturing a cornea,
2	comprising:
3	a thermokeratoplastic probe which has a tip that can be placed in contact
4	with the cornea; and,
5	a power supply which provides no more than 1.2 watts of power to said
6	thermokerator lastic probe for a time duration no greater than 1 second.

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1	17	(New) The system as recited in claim 16, further comprising a
2	ground pad	that provides a return path for the power provided to said
3	thermokera	toplastic probe.
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1	18.	(New) The system as recited in claim 16, wherein said
2	-thermokera	toplastic probe includes a tip which has a length between 300 and 600
3	microns.	
	8	4
1	19.	(New) The system as recited in claim 16, wherein said a following formula to said to plastic probe includes a handle, a first connector attached to said
2	thermokera	toplastic probe includes a handle, a first connector attached to said
3		a second connector that mates with said first connector.
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1	28.	(New) The system as recited in claim 18, wherein said
2	thermokeral	atoplastie-probe includes a stop that limits an insertion depth of said
3	tip into the	
	1	(
1	-21 .	(New) The system as recited in claim 18, wherein said tip is located
2	at a distal er	nd of a spring beam.

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